

QIAOXIN N-Channel Super Trench Power MOSFET

Description

The VCRR60T12AD uses **Super Trench** technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{DS(on)}$ and Q_g . This device is ideal for high-frequency switching and synchronous rectification.

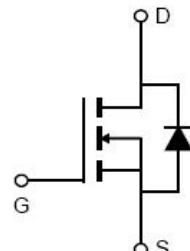
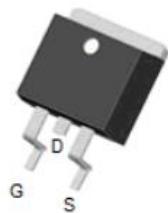
Application

- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification

General Features

- $V_{DS} = 60V, I_D = 120A$
- $R_{DS(on)} < 4.0m\Omega @ V_{GS}=10V$ (Typ:3.5mΩ)
- $R_{DS(on)} < 5.0m\Omega @ V_{GS}=4.5V$ (Typ:4.0mΩ)
- Excellent gate charge x $R_{DS(on)}$ product(FOM)
- Very low on-resistance $R_{DS(on)}$
- 175 °C operating temperature
- Pb-free lead plating

TO-263



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package
VCRR60T12AD		TO-263

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous (Silicon Limited)	I_D	120	A
Drain Current-Continuous($T_c=100^\circ C$)	$I_D (100^\circ C)$	100	A
Pulsed Drain Current	I_{DM}	480	A
Maximum Power Dissipation	P_D	180	W
Derating factor		1.2	W/°C
Single pulse avalanche energy ^(Note 1)	E_{AS}	500	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	°C

Thermal Characteristic

Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.83	°C/W
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Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

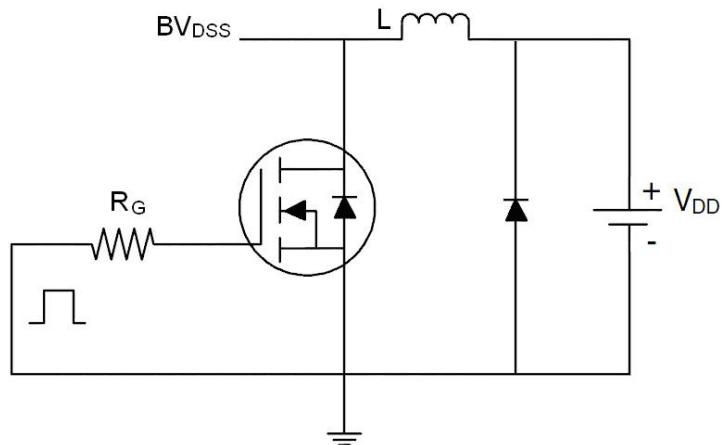
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60		-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	±100	nA
On Characteristics						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.0	1.7	2.4	V
Drain-Source On-State Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=60\text{A}$	-	3.5	4.0	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=60\text{A}$	-	4.0	5.0	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=60\text{A}$	40	-	-	S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	4000	-	PF
Output Capacitance	C_{oss}		-	680	-	PF
Reverse Transfer Capacitance	C_{rss}		-	23	-	PF
Switching Characteristics (Note 2)						
Turn-on Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=30\text{V}, I_{\text{D}}=60\text{A}$ $V_{\text{GS}}=10\text{V}, R_{\text{G}}=4.7\Omega$	-	11	-	nS
Turn-on Rise Time	t_r		-	5	-	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	56	-	nS
Turn-Off Fall Time	t_f		-	12	-	nS
Total Gate Charge	Q_g	$V_{\text{DS}}=30\text{V}, I_{\text{D}}=60\text{A}, V_{\text{GS}}=10\text{V}$	-	67	-	nC
Gate-Source Charge	Q_{gs}		-	12	-	nC
Gate-Drain Charge	Q_{gd}		-	8.5	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{s}}=120\text{A}$	-		1.2	V
Diode Forward Current	I_{s}		-	-	120	A
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}, I_F = I_s$ $dI/dt = 100\text{A}/\mu\text{s}$	-	48	-	nS
Reverse Recovery Charge	Q_{rr}		-	60	-	nC

Notes:

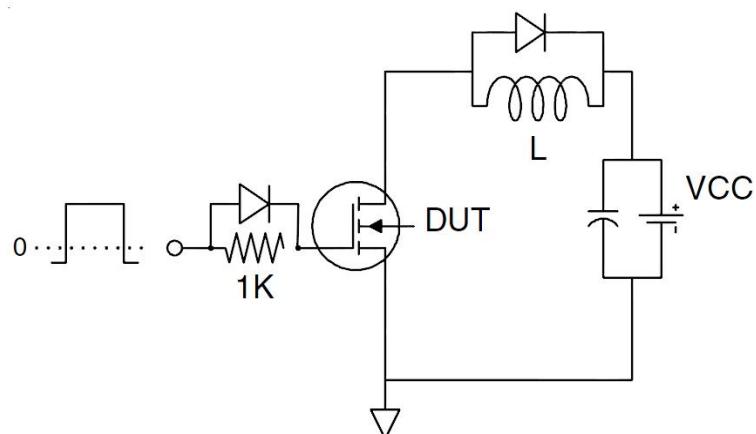
1. EAS condition : $T_j=25^\circ\text{C}, V_{\text{DD}}=30\text{V}, V_G=10\text{V}, L=0.5\text{mH}, R_g=25\Omega$
2. Guaranteed by design, not subject to production
3. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink k , assuming a maximum junction temperature of $T_J(\text{MAX})=175^\circ\text{C}$. The SOA curve provides a single pulse rating.

Test Circuit

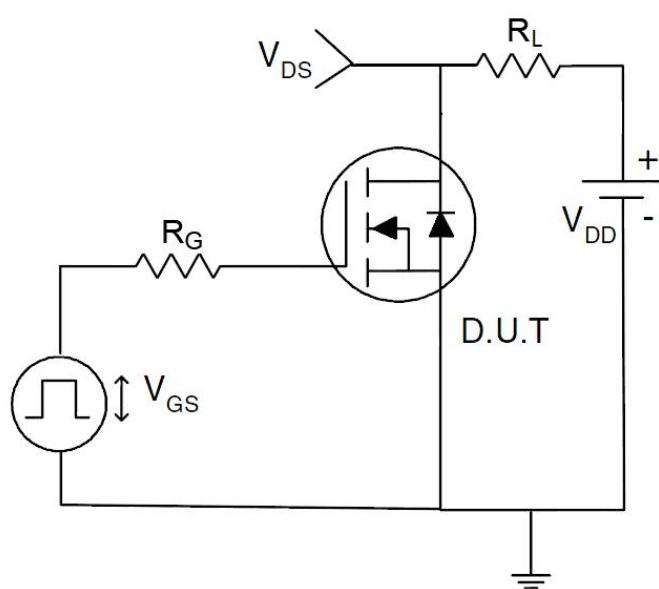
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics

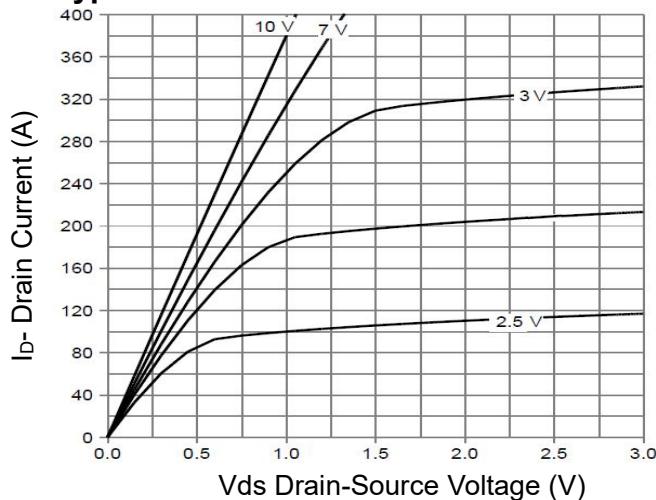


Figure 1 Output Characteristics

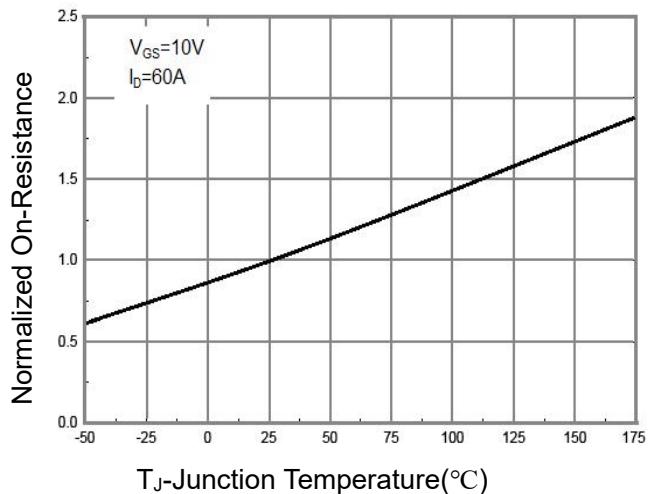


Figure 4 Rdson-JunctionTemperature

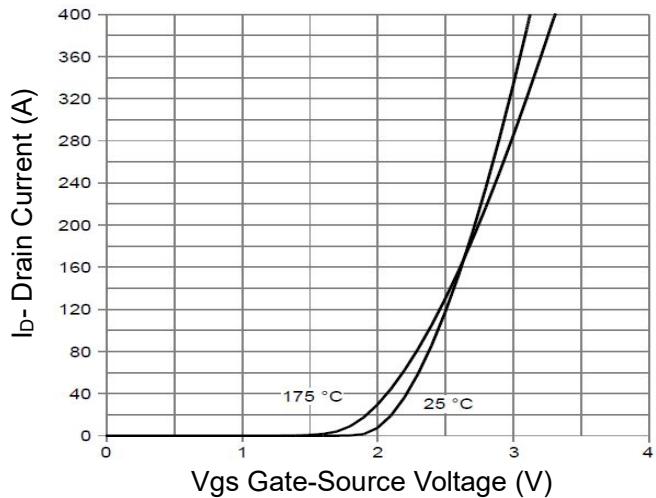


Figure 2 Transfer Characteristics

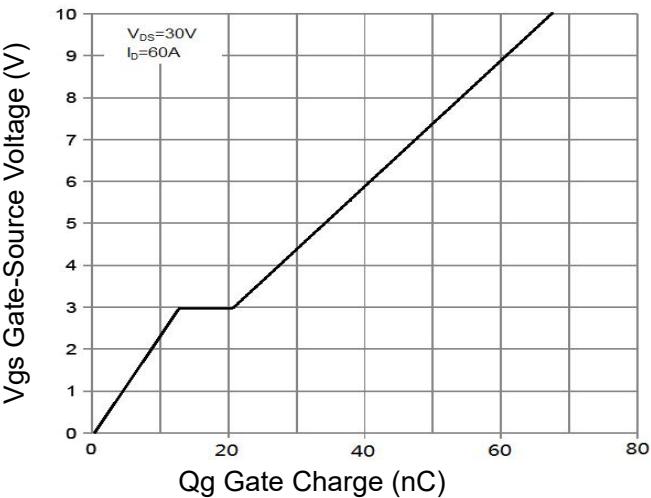


Figure 5 Gate Charge

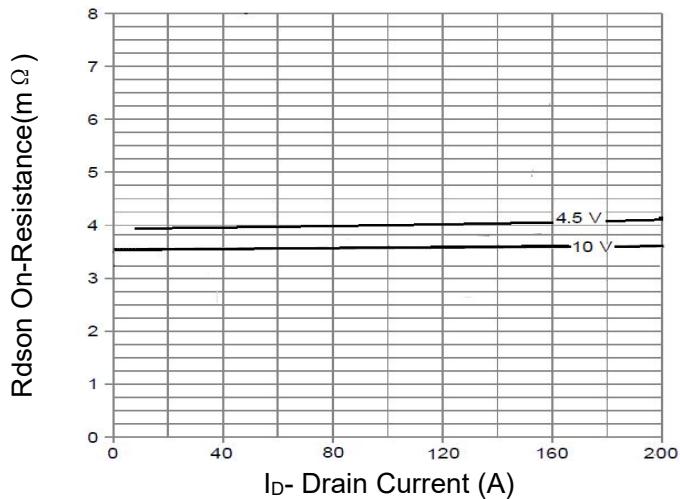


Figure 3 Rdson- Drain Current

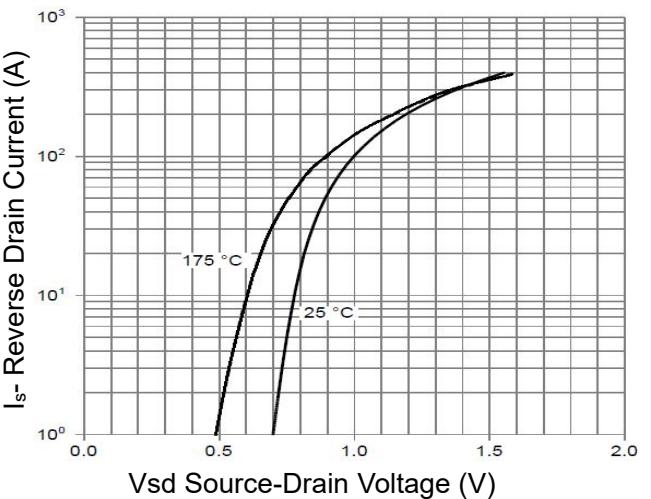


Figure 6 Source- Drain Diode Forw

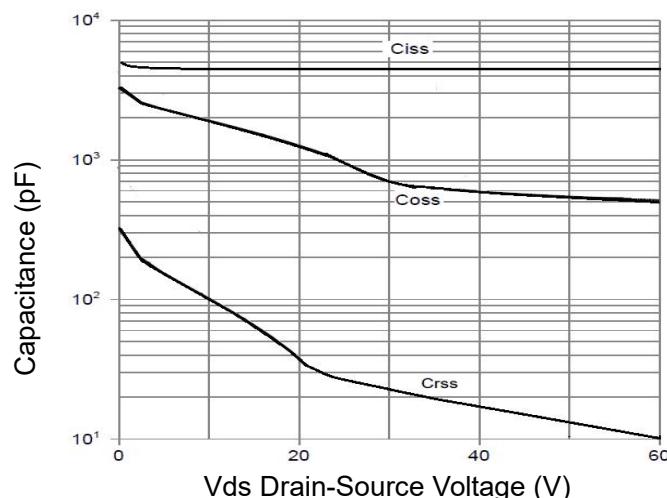


Figure 7 Capacitance vs Vds

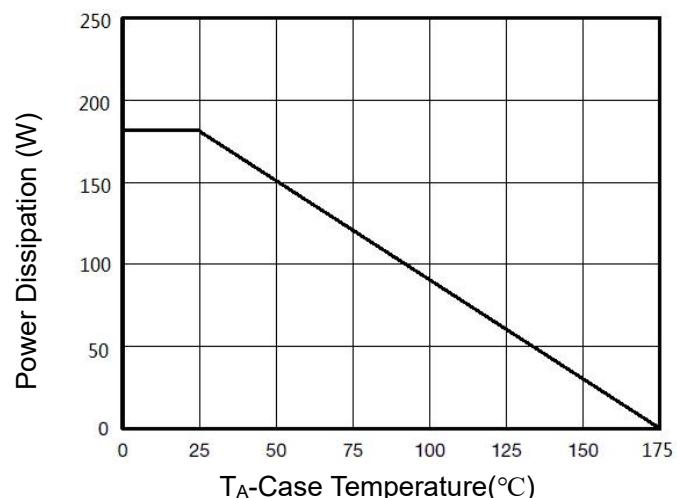


Figure 9 Power De-rating

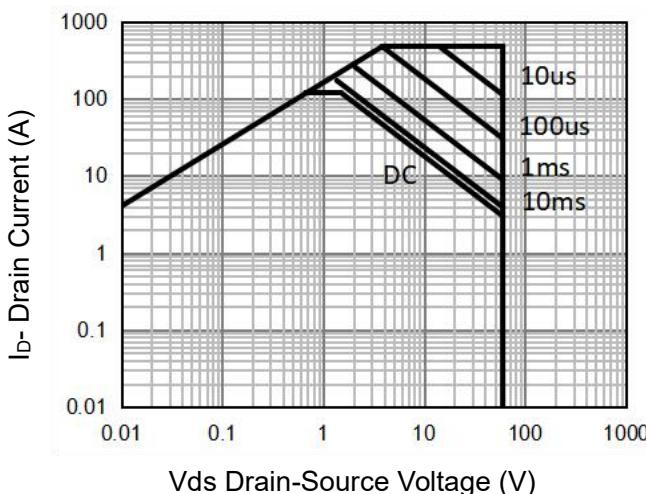


Figure 8 Safe Operation Area (Note 3)

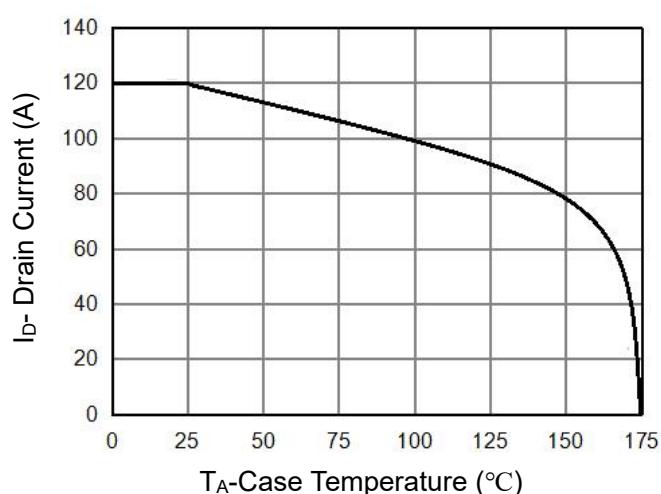


Figure 10 Current De-rating

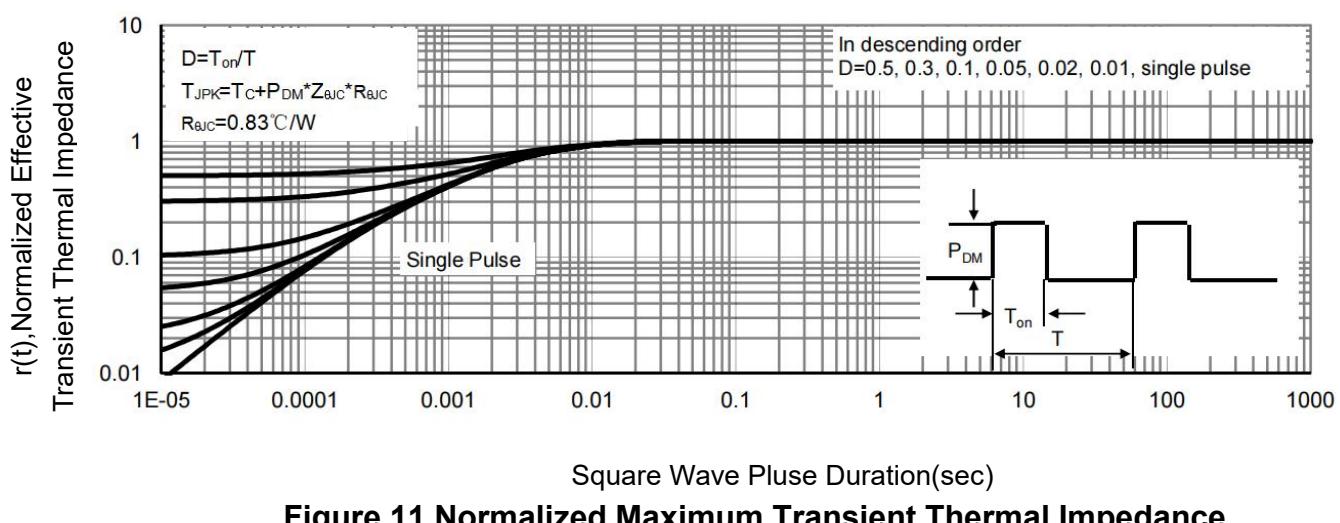
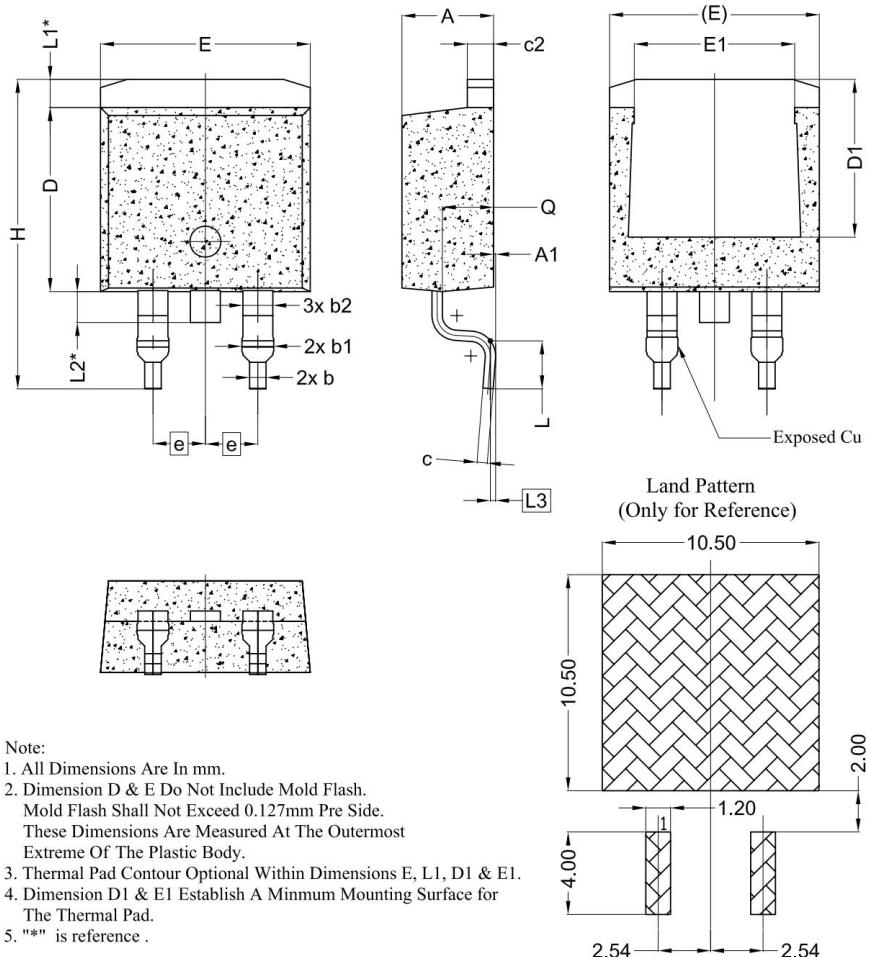


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-263-2L Package Information



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	4.24	4.44	4.64
A1	0.00	0.10	0.25
b	0.70	0.80	0.90
b1	1.20	1.55	1.75
b2	1.20	1.45	1.70
c	0.40	0.50	0.60
c2	1.15	1.27	1.40
D	8.82	8.92	9.02
D1	6.86	7.65	—
E	9.96	10.16	10.36
E1	6.89	7.77	7.89
e	2.54 BSC		
H	14.61	15.00	15.88
L	1.78	2.32	2.79
L1	1.36 REF.		
L2	1.50 REF.		
L3	0.25 BSC		
Q	2.30	2.48	2.70

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